

Application/Control No.	Applicant(s)/Patent under Reexamination
10/781,676	TAKEI, KEN
Examiner	Art Unit
Tan Ho	2821

	SEARCHED					
Class	Subclass	Subclass Date				
343	700MS	4/1/05	てけ			
	702					
	767					
	770		<i>\\</i>			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
343	702	41/05	上.H.	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
West	43/05	7.4.		
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